

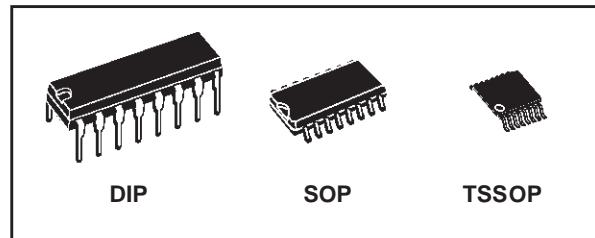
## QUAD 2 CHANNEL MULTIPLEXER

- HIGH SPEED:  $t_{PD} = 4\text{ns}$  (TYP.) at  $V_{CC} = 5\text{V}$
- LOW POWER DISSIPATION:  
 $I_{CC} = 4\mu\text{A}$ (MAX.) at  $T_A=25^\circ\text{C}$
- HIGH NOISE IMMUNITY:  
 $V_{NIH} = V_{NIL} = 28\%$   $V_{CC}$  (MIN.)
- 50Ω TRANSMISSION LINE DRIVING CAPABILITY
- SYMMETRICAL OUTPUT IMPEDANCE:  
 $|I_{OHI}| = I_{OL} = 24\text{mA}$  (MIN)
- BALANCED PROPAGATION DELAYS:  
 $t_{PLH} \approx t_{PHL}$
- OPERATING VOLTAGE RANGE:  
 $V_{CC}$  (OPR) = 2V to 6V
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 157
- IMPROVED LATCH-UP IMMUNITY

### DESCRIPTION

The 74AC157 is an advanced high-speed CMOS QUAD 2-CHANNEL MULTIPLEXER fabricated with sub-micron silicon gate and double-layer metal wiring C<sup>2</sup>MOS technology.

It consists of four 2-input digital multiplexer with common SELECT and STROBE inputs. It is a non-inverting multiplexer. When the STROBE



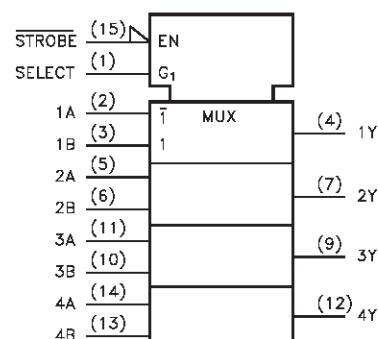
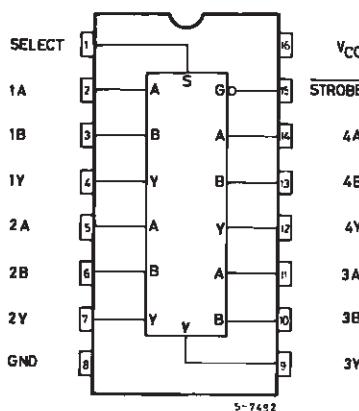
### ORDER CODES

PACKAGE	TUBE	T & R
DIP	74AC157B	
SOP	74AC157M	74AC157MTR
TSSOP		74AC157TTR

input is held high selection of data is inhibit and all the outputs become low. The SELECT decoding determines whether the A or B inputs get routed to their corresponding Y outputs.

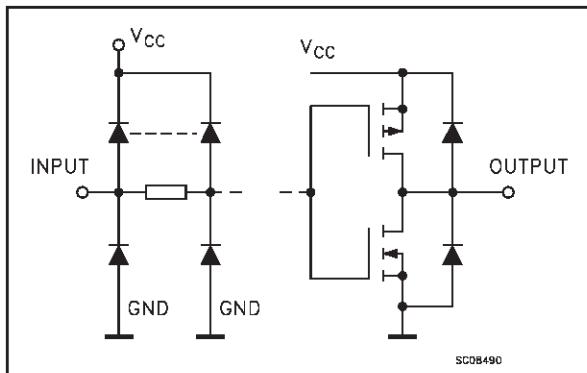
All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

### PIN CONNECTION AND IEC LOGIC SYMBOLS



# 74AC157

## INPUT AND OUTPUT EQUIVALENT CIRCUIT



## PIN DESCRIPTION

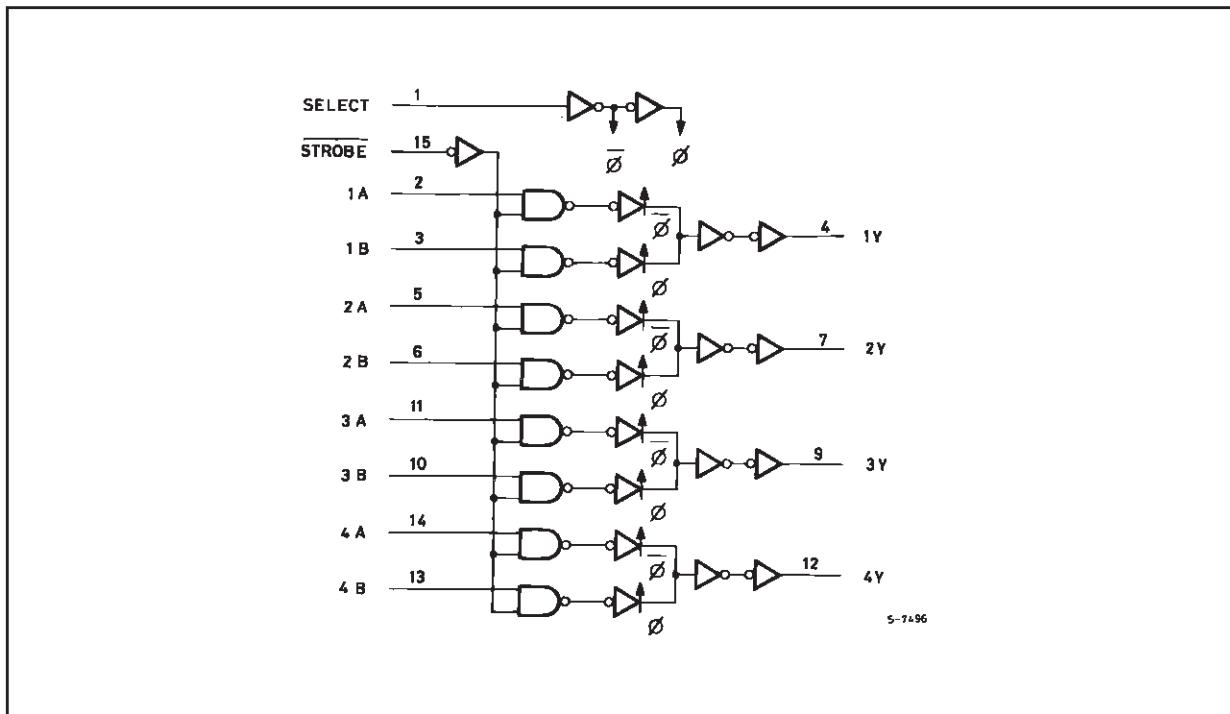
PIN No	SYMBOL	NAME AND FUNCTION
1	SELECT	Common Data Select Inputs
2, 5, 11, 14	1A to 4A	Data Inputs From Source A
3, 6, 10, 13	1B to 4B	Data Inputs From Source B
4, 7, 9, 12	1Y to 4Y	Multiplexer Outputs
15	STROBE	Strobe Input
8	GND	Ground (0V)
16	V <sub>CC</sub>	Positive Supply Voltage

## TRUTH TABLE

INPUTS				OUTPUT
STROBE	SELECT	A	B	Y
H	X	X	X	L
L	L	L	X	L
L	L	H	X	H
L	H	X	L	L
L	H	X	H	H

X : Don't Care

## LOGIC DIAGRAM



**ABSOLUTE MAXIMUM RATINGS**

<b>Symbol</b>	<b>Parameter</b>	<b>Value</b>	<b>Unit</b>
$V_{CC}$	Supply Voltage	-0.5 to +7	V
$V_I$	DC Input Voltage	-0.5 to $V_{CC} + 0.5$	V
$V_O$	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
$I_{IK}$	DC Input Diode Current	$\pm 20$	mA
$I_{OK}$	DC Output Diode Current	$\pm 20$	mA
$I_O$	DC Output Current	$\pm 50$	mA
$I_{CC}$ or $I_{GND}$	DC $V_{CC}$ or Ground Current	$\pm 200$	mA
$T_{stg}$	Storage Temperature	-65 to +150	°C
$T_L$	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

**RECOMMENDED OPERATING CONDITIONS**

<b>Symbol</b>	<b>Parameter</b>	<b>Value</b>	<b>Unit</b>
$V_{CC}$	Supply Voltage	2 to 6	V
$V_I$	Input Voltage	0 to $V_{CC}$	V
$V_O$	Output Voltage	0 to $V_{CC}$	V
$T_{op}$	Operating Temperature	-55 to 125	°C
dt/dv	Input Rise and Fall Time $V_{CC} = 3.0, 4.5$ or $5.5V$ (note 1)	8	ns/V

1)  $V_{IN}$  from 30% to 70% of  $V_{CC}$

## DC SPECIFICATIONS

Symbol	Parameter	Test Condition		Value						Unit	
		$V_{CC}$ (V)		$T_A = 25^\circ C$			$-40 \text{ to } 85^\circ C$		$-55 \text{ to } 125^\circ C$		
				Min.	Typ.	Max.	Min.	Max.	Min.		
$V_{IH}$	High Level Input Voltage	3.0	$V_O = 0.1 \text{ V or } V_{CC}-0.1\text{V}$	2.1	1.5		2.1		2.1	V	
		4.5		3.15	2.25		3.15		3.15		
		5.5		3.85	2.75		3.85		3.85		
$V_{IL}$	Low Level Input Voltage	3.0	$V_O = 0.1 \text{ V or } V_{CC}-0.1\text{V}$		1.5	0.9		0.9		V	
		4.5			2.25	1.35		1.35			
		5.5			2.75	1.65		1.65			
$V_{OH}$	High Level Output Voltage	3.0	$I_O=-50 \mu A$	2.9	2.99		2.9		2.9	V	
		4.5	$I_O=-50 \mu A$	4.4	4.49		4.4		4.4		
		5.5	$I_O=-50 \mu A$	5.4	5.49		5.4		5.4		
		3.0	$I_O=-12 \text{ mA}$	2.56			2.46		2.46		
		4.5	$I_O=-24 \text{ mA}$	3.86			3.76		3.76		
		5.5	$I_O=-24 \text{ mA}$	4.86			4.76		4.76		
$V_{OL}$	Low Level Output Voltage	3.0	$I_O=50 \mu A$		0.002	0.1		0.1		V	
		4.5	$I_O=50 \mu A$		0.001	0.1		0.1			
		5.5	$I_O=50 \mu A$		0.001	0.1		0.1			
		3.0	$I_O=12 \text{ mA}$			0.36		0.44			
		4.5	$I_O=24 \text{ mA}$			0.36		0.44			
		5.5	$I_O=24 \text{ mA}$			0.36		0.44			
$I_I$	Input Leakage Current	5.5	$V_I = V_{CC} \text{ or GND}$			$\pm 0.1$		$\pm 1$		$\mu A$	
$I_{CC}$	Quiescent Supply Current	5.5	$V_I = V_{CC} \text{ or GND}$			4		40		$\mu A$	
$I_{OLD}$	Dynamic Output Current (note 1, 2)	5.5	$V_{OLD} = 1.65 \text{ V max}$					75		75 mA	
$I_{OHD}$			$V_{OHD} = 3.85 \text{ V min}$					-75		-75 mA	

1) Maximum test duration 2ms, one output loaded at time

2) Incident wave switching is guaranteed on transmission lines with impedances as low as  $50\Omega$

AC ELECTRICAL CHARACTERISTICS ( $C_L = 50 \text{ pF}$ ,  $R_L = 500 \Omega$ , Input  $t_r = t_f = 3\text{ns}$ )

Symbol	Parameter	Test Condition		Value						Unit	
		$V_{CC}$ (V)		$T_A = 25^\circ\text{C}$			$-40 \text{ to } 85^\circ\text{C}$		$-55 \text{ to } 125^\circ\text{C}$		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
$t_{PLH}$	Propagation Delay Time SELECT to Y	3.3 <sup>(*)</sup>		1.5	6.5	11.0	1.5	12.0	1.5	12.0	ns
		5.0 <sup>(**)</sup>		1.5	5.0	8.5	1.5	9.5	1.5	9.5	
$t_{PLH}$	Propagation Delay Time STROBE to Y	3.3 <sup>(*)</sup>		1.5	6.5	11.0	1.5	12.0	1.5	12.0	ns
		5.0 <sup>(**)</sup>		1.5	5.5	9.0	1.5	10.0	1.5	10.0	
$t_{PLH}$	Propagation Delay Time A, B to Y	3.3 <sup>(*)</sup>		1.5	5.0	8.0	1.5	9.0	1.5	9.0	ns
		5.0 <sup>(**)</sup>		1.5	4.0	6.5	1.5	7.0	1.5	7.0	

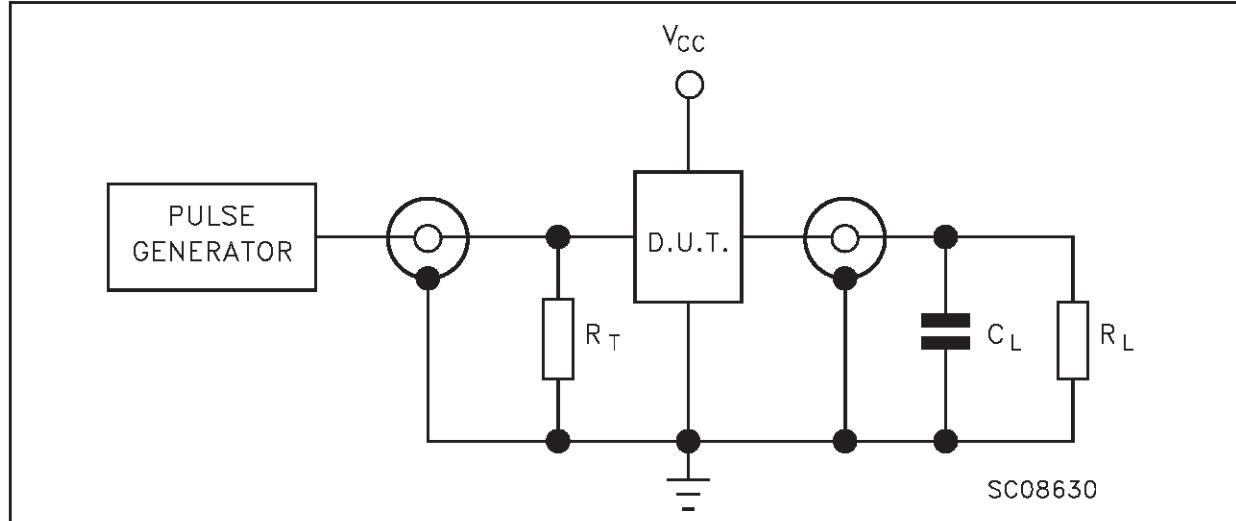
<sup>(\*)</sup> Voltage range is  $3.3\text{V} \pm 0.3\text{V}$ <sup>(\*\*)</sup> Voltage range is  $5.0\text{V} \pm 0.5\text{V}$ 

## CAPACITIVE CHARACTERISTICS

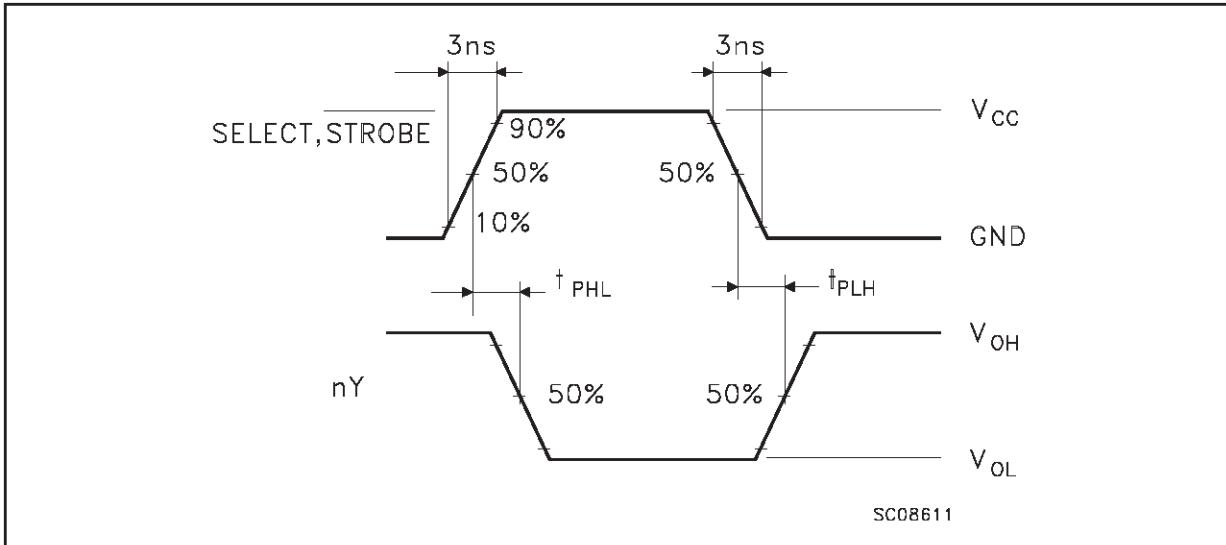
Symbol	Parameter	Test Condition		Value						Unit	
		$V_{CC}$ (V)		$T_A = 25^\circ\text{C}$			$-40 \text{ to } 85^\circ\text{C}$		$-55 \text{ to } 125^\circ\text{C}$		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
$C_{IN}$	Input Capacitance	5.0			5						pF
$C_{PD}$	Power Dissipation Capacitance (note 1)	5.0	$f_{IN} = 10\text{MHz}$		33						pF

1)  $C_{PD}$  is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation.  $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/n$  (per circuit)

## TEST CIRCUIT

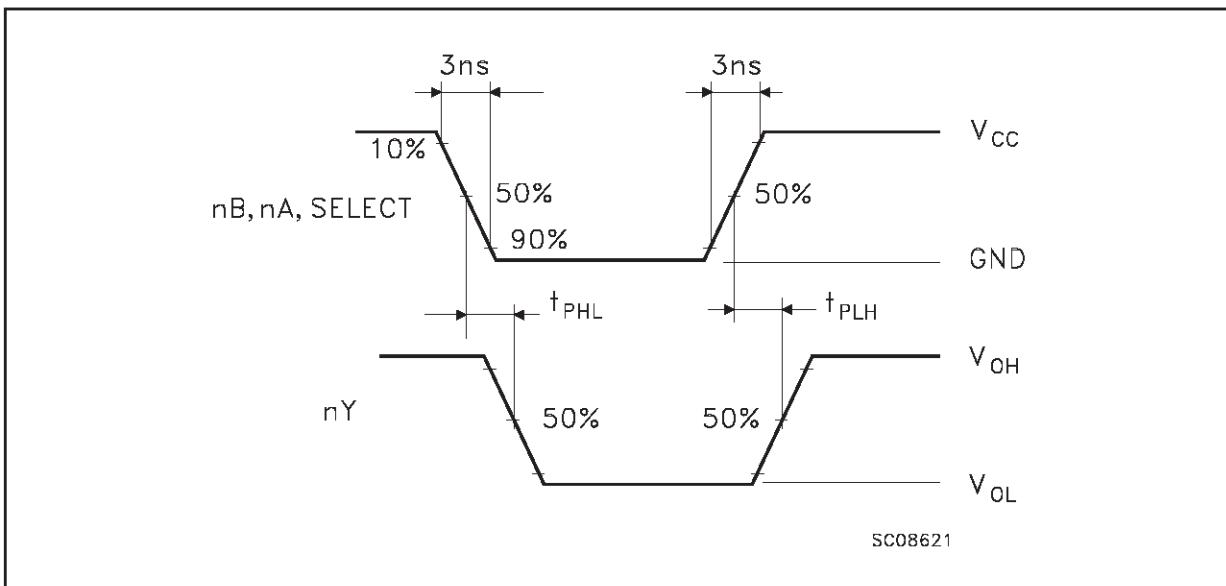
 $C_L = 50\text{pF}$  or equivalent (includes jig and probe capacitance) $R_L = R_1 = 500\Omega$  or equivalent $R_T = Z_{OUT}$  of pulse generator (typically  $50\Omega$ )

**WAVEFORM 1: PROPAGATION DELAYS FOR INVERTING CONDITIONS (f=1MHz; 50% duty cycle)**



SC08611

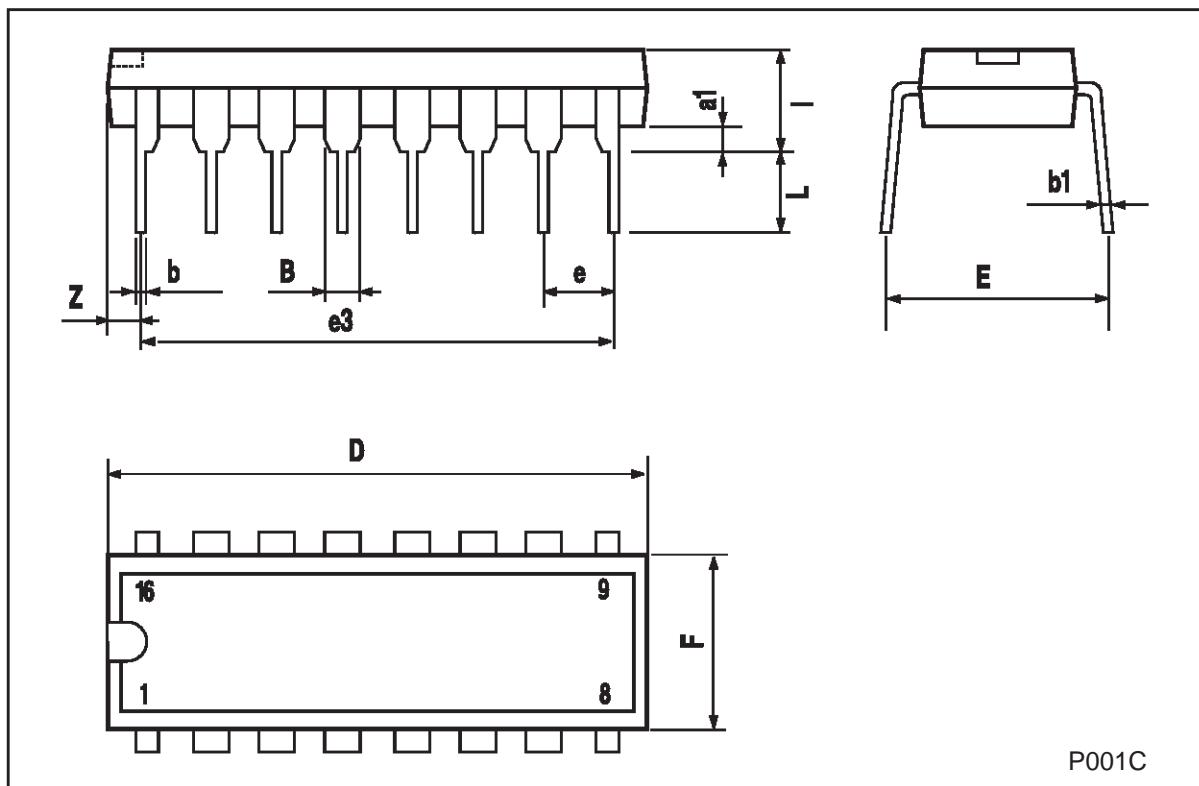
**WAVEFORM 2: PROPAGATION DELAYS FOR NON-INVERTING CONDITIONS (f=1MHz; 50% duty cycle)**



SC08621

**Plastic DIP-16 (0.25) MECHANICAL DATA**

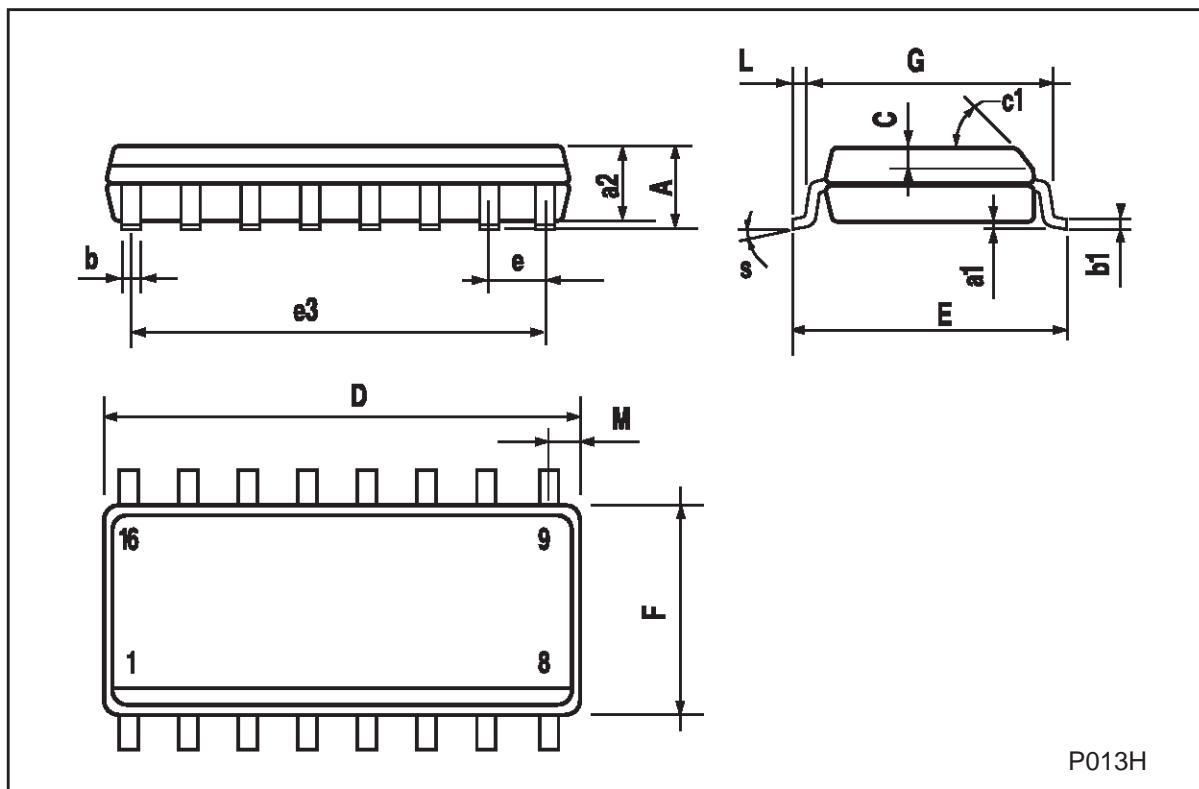
DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
a1	0.51			0.020		
B	0.77		1.65	0.030		0.065
b		0.5			0.020	
b1		0.25			0.010	
D			20			0.787
E		8.5			0.335	
e		2.54			0.100	
e3		17.78			0.700	
F			7.1			0.280
I			5.1			0.201
L		3.3			0.130	
Z			1.27			0.050



P001C

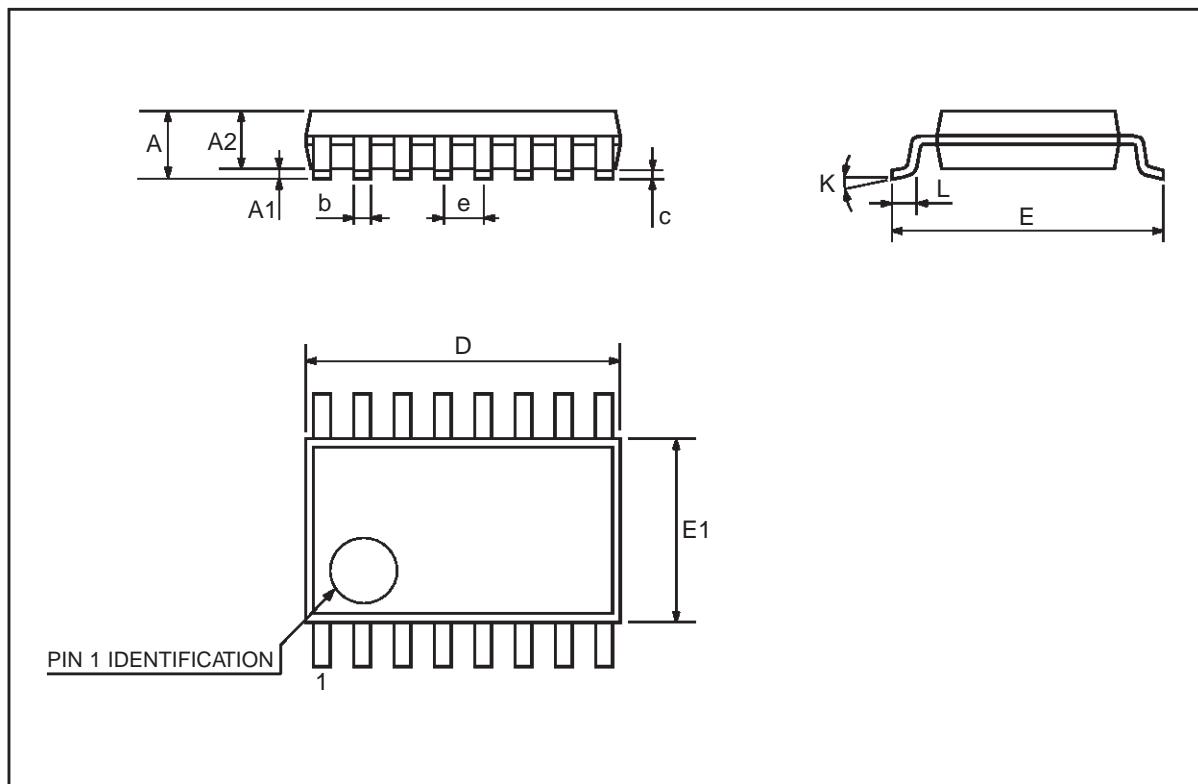
## SO-16 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.2	0.004		0.007
a2			1.65			0.064
b	0.35		0.46	0.013		0.018
b1	0.19		0.25	0.007		0.010
C		0.5			0.019	
c1		45 (typ.)				
D	9.8		10	0.385		0.393
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		8.89			0.350	
F	3.8		4.0	0.149		0.157
G	4.6		5.3	0.181		0.208
L	0.5		1.27	0.019		0.050
M			0.62			0.024
S		8 (max.)				



<b>TSSOP16 MECHANICAL DATA</b>
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DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.1			0.433
A1	0.05	0.10	0.15	0.002	0.004	0.006
A2	0.85	0.9	0.95	0.335	0.354	0.374
b	0.19		0.30	0.0075		0.0118
c	0.09		0.20	0.0035		0.0079
D	4.9	5	5.1	0.193	0.197	0.201
E	6.25	6.4	6.5	0.246	0.252	0.256
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	$0^\circ$	$4^\circ$	$8^\circ$	$0^\circ$	$4^\circ$	$8^\circ$
L	0.50	0.60	0.70	0.020	0.024	0.028



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